

Notice of References Cited	Application/Control No. 10/712,706	Applicant(s)/Patent Under Reexamination ROOT ET AL.	
	Examiner Jason Proctor	Art Unit 2123	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	David E. Root, John Wood, and Nick Tufillaro; "New Techniques for Non-Linear Behavioral Modeling of Microwave/RD ICs from Simulation and Nonlinear Microwave Measurements"; June 2003; ACM; Proceedings of the 40th conference on Design Automation; pages 85-90
	V	John Wood and David E. Root; "The Behavioral Modeling of Microwave/RF ICs using Nonlinear Time Series Analysis"; June 2003; IEEE; pages 791-794
	W	David E. Root, John Wood, Nick Tufillaro, Dominique Schreurs, and Alexander Pekker; "Systematic behavioral modeling of nonlinear microwave/RF circuits in the time domain using techniques from nonlinear dynamical systems"; 2002; IEEE; pages 71-74
	X	D. Schreurs, J. Wood, N. Tufillaro, D. Usikov, L. Barford, and D.E. Root; "The Construction and Evaluation of Behavioral Models for Microwave Devices Based on Time-Domain Large-Signal Measurements"; 2000; IEEE; pages 819-822

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/712,706	Applicant(s)/Patent Under Reexamination ROOT ET AL.	
	Examiner Jason Proctor	Art Unit 2123	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Jens Verspecht; "Describing Functions Can Better Model Hard Nonlinearities In The Frequency Domain Than The Volterra Theory"; 1995; pages 1-17
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.